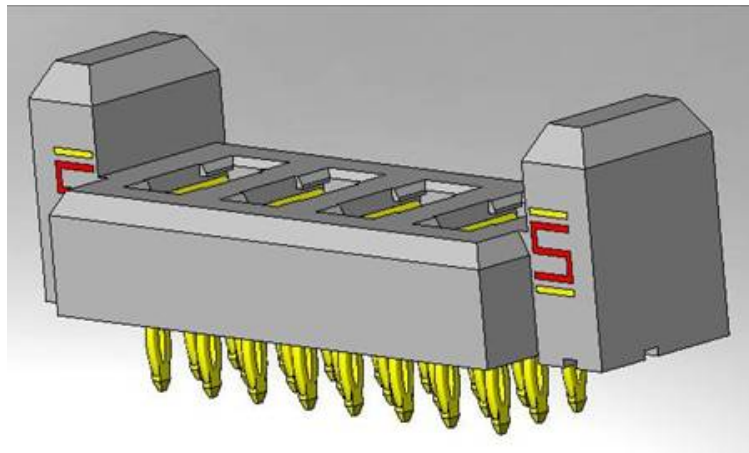
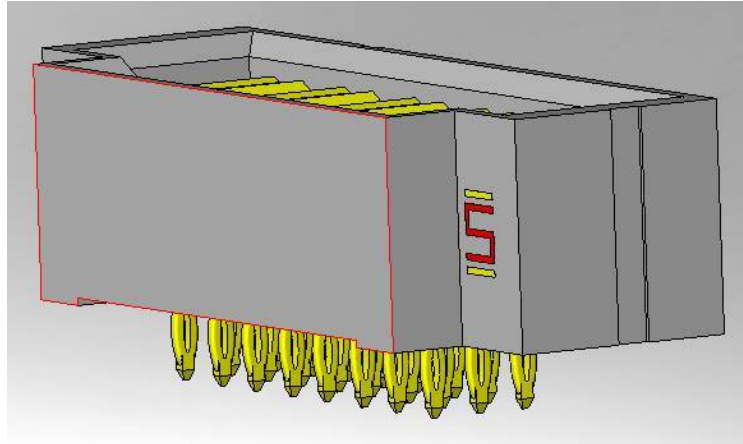




Project Number: Design Qualification Test Report		Tracking Code: 226661_Report_Rev_1		
Requested by: John Reid		Date: 11/29/2012	Product Rev: N/A	
Part #: UPS-08-04.0-03-T-PV\UPT-08-03.0-03-T-PV		Lot #: N/A	Tech: Troy Cook	Eng: Eric Mings
Part description: UPS\UPT				Qty to test: 8
Test Start: 11/06/2012	Test Completed: 11/26/2012			



DESIGN QUALIFICATION TEST REPORT

UPS\UPT

UPS-08-04.0-03-T-PV\UPT-08-03.0-03-T-PV

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

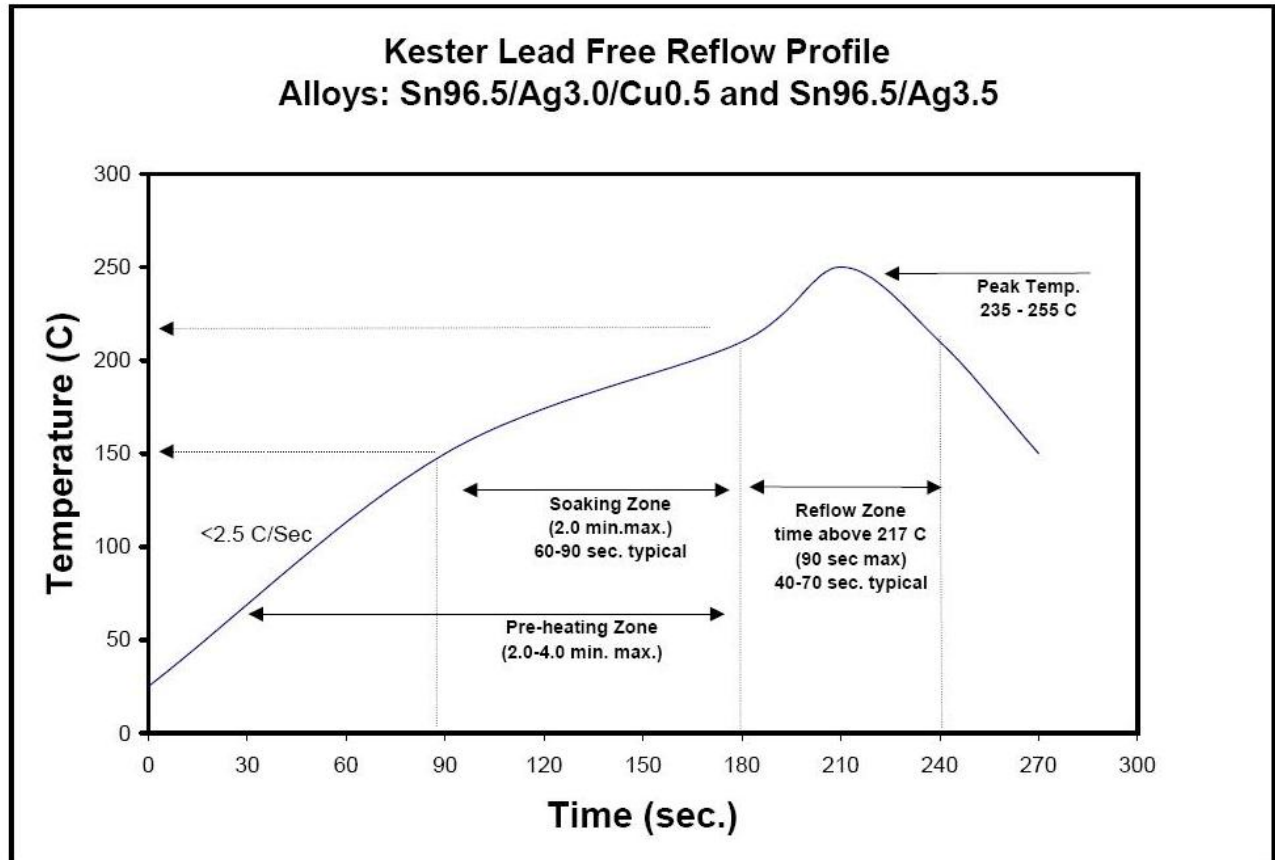
To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.
- 10) Samtec Test PCBs used: PCB-103552-TST

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)

FLOWCHARTS**Durability/Mating/Unmating/Gaps**

TEST STEP	GROUP A1 8 Boards (Nominal Gap)
01	Contact Gaps
02	LLCR-1
03	Forces - Mating / Unmating
04	25 Cycles
05	Forces - Mating / Unmating
06	Clean w/Compressed Air
07	Contact Gaps
08	LLCR-2
09	Thermal Shock (Mated and Undisturbed)
10	LLCR-3
11	Cyclic Humidity (Mated and Undisturbed)
12	LLCR-4
13	Forces - Mating / Unmating

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

Mating / Unmating Forces = EIA-364-13

Contact Gaps / Height - No standard method. Usually measured optically.

Gaps to be taken on a minimum of 20% of each part tested

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

CONTACT GAPS:

- 1) Gaps above the surrounding plastic surface were measured before and after stressing the contacts (e.g. thermal aging, mechanical cycling, etc.).
- 2) Typically, all contacts on the connector are measured.

MATING/UNMATING:

- 1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
- 2) The full insertion position was to within 0.003” to 0.004” of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. +5.1 to +10.0 mOhms:----- Minor
 - c. +10.1 to +15.0 mOhms: ----- Acceptable
 - d. +15.1 to +50.0 mOhms: ----- Marginal
 - e. +50.1 to +2000 mOhms: ----- Unstable
 - f. $>+2000$ mOhms:----- Open Failure

RESULTS

Mating\Unmating Forces

- **Initial**
 - **Mating**
 - **Min** -----13.46 Lbs
 - **Max** -----15.04 Lbs
 - **Unmating**
 - **Min** -----13.54 Lbs
 - **Max** -----15.84 Lbs
- **After 25 Cycles**
 - **Mating**
 - **Min** -----14.03 Lbs
 - **Max** -----15.98 Lbs
 - **Unmating**
 - **Min** -----12.74 Lbs
 - **Max** -----14.14 Lbs
- **After Humidity**
 - **Mating**
 - **Min** -----10.34 Lbs
 - **Max** -----12.95 Lbs
 - **Unmating**
 - **Min** -----10.02 Lbs
 - **Max** -----11.92 Lbs

RESULTS Continued**LLCR Durability: (56 points)**

- **Initial** -----0.72mOhms Max
- **Durability, 25 Cycles**
 - <= +5.0 mOhms ----- 56 Points ----- Stable
 - +5.1 to +10.0 mOhms -----0 Points ----- Minor
 - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +2000 mOhms-----0 Points ----- Unstable
 - >+2000 mOhms -----0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 56 Points ----- Stable
 - +5.1 to +10.0 mOhms -----0 Points ----- Minor
 - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +2000 mOhms-----0 Points ----- Unstable
 - >+2000 mOhms -----0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 56 Points ----- Stable
 - +5.1 to +10.0 mOhms -----0 Points ----- Minor
 - +10.1 to +15.0 mOhms -----0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms -----0 Points ----- Marginal
 - +50.1 to +2000 mOhms-----0 Points ----- Unstable
 - >+2000 mOhms -----0 Points ----- Open Failure

DATA SUMMARIES**Mating\Unmating Force**

	Initial				25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	59.87	13.46	60.23	13.54	62.41	14.03	56.67	12.74
Maximum	66.90	15.04	70.46	15.84	71.08	15.98	62.89	14.14
Average	62.79	14.12	64.85	14.58	66.40	14.93	59.53	13.38
St Dev	2.78	0.62	3.36	0.76	2.37	0.53	2.53	0.57
Count	8	8	8	8	8	8	8	8
	After Humidity							
	Mating		Unmating					
	Newton's	Force (Lbs)	Newton's	Force (Lbs)				
Minimum	46.00	10.34	44.56	10.02				
Maximum	57.58	12.95	53.00	11.92				
Average	52.50	11.80	49.72	11.18				
St Dev	4.55	1.02	3.30	0.74				
Count	8	8	8	8				

DATA SUMMARIES Continued**LLCR Durability:**

- 1) A total of 56 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms:----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms----- Unstable
 - f. $>+2000$ mOhms:----- Open Failure

LLCR Measurement Summaries by Pin Type				
	2012-11-6	2012-11-8	2012-11-13	2012-11-26
Date	2012-11-6	2012-11-8	2012-11-13	2012-11-26
Room Temp (Deg C)	22	22	22	22
Rel Humidity (%)	30	30	31	31
Technician	Troy Cook	Troy Cook	Troy Cook	Troy Cook
mOhm values	Actual Initial	Delta 25 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	0.67	0.07	0.69	0.48
St. Dev.	0.03	0.05	0.81	0.57
Min	0.54	0.00	0.02	0.02
Max	0.72	0.19	2.93	2.75
Summary Count	56	56	56	56
Total Count	56	56	56	56

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
25 Cycles	56	0	0	0	0	0
Therm Shck	56	0	0	0	0	0
Humidity	56	0	0	0	0	0

EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** MO-04**Description:** Multimeter /Data Acquisition System**Manufacturer:** Keithley**Model:** 2700**Serial #:** 0798688**Accuracy:** See Manual

... Last Cal: 04/30/2012, Next Cal: 04/30/2013

Equipment #: TCT-04**Description:** Dillon Quantrol TC2 Test Stand**Manufacturer:** Dillon Quantrol**Model:** TC2**Serial #:** 04-1041-04**Accuracy:** Speed Accuracy: +/- 5% of indicated speed; Displacement: +/- 5 micrometers.

... Last Cal: 05/21/2012, Next Cal: 05/21/2013

Equipment #: THC-02**Description:** Temperature/Humidity Chamber**Manufacturer:** Thermotron**Model:** SE-1000-6-6**Serial #:** 31808**Accuracy:** See Manual

... Last Cal: 02/16/2012, Next Cal: 02/16/2013

Equipment #: TSC-01**Description:** Vertical Thermal Shock Chamber**Manufacturer:** Cincinnatti Sub Zero**Model:** VTS-3-6-6-SC/AC**Serial #:** 10-VT14993**Accuracy:** See Manual

... Last Cal: 05/18/2012, Next Cal: 05/18/2013